

AMENDMENTS TO THE SPECIFICATION

Please replace the paragraph bridging pages 2-3 of the specification with the following amended paragraph:

The invention provides an optical information recording medium which comprises a substrate having successively disposed thereon a light-reflective layer, a recording layer and a cover layer, wherein information can be recorded on and reproduced from the recording layer by irradiating a laser beam from a side at which the cover layer is disposed, and a surface of the light-reflective layer at a side at which the recording layer is disposed has a central surface average roughness S_{Ra} of 30 nm or smaller and a number of projections having a height from a reference plane of 50 nm or greater, as determined with an atomic force microscope (AFM), of 30 (number/90 μm ~~angle~~square) or less.

Please replace the first full paragraph on page 3 of the specification with the following amended paragraph:

An optical information recording medium according to the present invention comprises a substrate having a light-reflective layer, a recording layer and a cover layer disposed in this sequence, wherein information can be recorded on and reproduced from the recording layer by irradiating a laser beam from a side at which the cover layer is disposed, and a surface of the light-reflective layer at a side at which the recording layer is disposed has a central surface average roughness S_{Ra} of 30 nm or smaller and a number of projections having a height from a reference plane of 50 nm or greater, as determined with an atomic force microscope (AFM), of 30 (number/90 μm ~~angle~~square) or less.

Please replace the second paragraph on page 6 of the specification with the following amended paragraph:

In the optical information recording medium of the invention, the surface of the light-reflective layer at a side at which the recording layer, to be described later, is disposed is characterized in that the central surface average roughness S_{Ra} is 30 nm or less and the number of projections having a height from a reference plane which is measured using an atomic force microscope (AFM) (hereinafter referred to simply as “reference plane”) of 50 nm or greater is 30 (number/90 μm anglesquare) or less. The reference plane as used herein refers to a plane at which an average of heights in the direction Z when determined using an atomic force microscope (AFM) is Z₀. In other words, the reference plane is a plane expressed by Z = Z₀ and parallel to the XY plane.

Please replace the paragraph bridging pages 6-7 of the specification with the following amended paragraph:

If the number of projections having a height from a reference plane on the surface of the light-reflective layer of 50 nm or greater exceeds 30 (number/90 μm anglesquare), reflected light is likely scattered, thus causing increased noise and impaired jitter and error rate. Although a very specific case, there arises a case of producing coating unevenness, recording void, increased noise and impaired jitter and error rate. The number of projections is preferably 15 (number/90 μm anglesquare) or less, and more preferably 5 (number/90 μm anglesquare) or less. The lower limit of the number of projections is ideally 0 (number/90 μm squareangle).

Please replace the second full paragraph on page 7 of the specification with the following amended paragraph:

It is noted that the central surface average roughness SRa is a value calculated after the cover layer is peeled off, the recording layer is removed using an alcohol-type solvent and a smooth area of the surface is measured using an atomic force microscope (AFM) (30 μm \times 30 μm ~~anglesquare~~).

Please replace the third full paragraph on page 7 of the specification with the following amended paragraph:

The above number of projections is a number of projections having a height from a reference plane of 50 nm or greater detected after the cover layer is peeled off, the recording layer is removed using an alcohol-type solvent and a smooth area of the surface is subjected to a three view-field measurement using an atomic force microscope (AFM) (30 μm \times 30 μm ~~anglesquare~~).

Please replace the paragraph bridging pages 20-21 with the following amended paragraph:

The optical information recording media were assessed for the central surface average roughness SRa, using SPA500 (manufactured by Seiko Instruments Inc.) under the following measuring conditions.

<Measuring Conditions>

Mode: AFM mode (contact mode)

Measuring probe: SI AF01 (spring constant: 0.1 N/m)

Scanning range: 30 μm ~~anglesquare~~

Scanning line: 512 \times 512

Scanning speed: 2 Hz

Please replace the first full paragraph on page 21 with the following amended paragraph:

The number of projections was measured using an AFM under the same conditions as those for the central surface average roughness SRa to find the number of projections per 90 μm angle-square by three view-field measurement of 30 μm anglesquare.

Please replace the paragraph bridging pages 21-22 under the Table with the following amended paragraph:

As seen from Table 1, all the optical information recording media of Examples 1 to 4 that have the central surface average roughness SRa of 30 nm or smaller and the number of projections having a height from a reference plane of 50 nm or greater of 30 (number/90 μm anglesquare) or less show a value of 10% or less in both of jitter and noise, revealing that the optical information recording media according to the present invention have excellent characteristics of suppressed noise and low jitter and hence have high reliability.

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